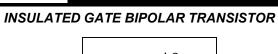
International

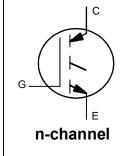
 $V_{CES} = 1200V$ $I_{C(Nominal)} = 75A$ $T_{J(max)} = 175^{\circ}C$ $V_{CE(on)} typ = 1.9V @ I_{C} = 75A$

Applications

- Medium Power Drives
- UPS
- HEV Inverter
- Welding
- Induction Heating



IRG7CH73K10EF



G	С	Е	
Gate	Collector	Emitter	

Features —	→ Benefits
	High efficiency in a wide range of applications and switching frequencies
	Improved Reliability due to rugged hard switching performance and higher power capability
Positive V _{CE (ON)} Temperature Coefficient	Excellent current sharing in parallel operation

Base part number		Standa	rd Pack	Orderable part number	
Base part number	Package Type	Form	Quantity		
IRG7CH73K10EF	Die on Film	Wafer	1	IRG7CH73K10EF	

Mechanical Parameter

Die Size	9.07 x 9.07	mm ²		
Minimum Street Width	75	μm		
Emiter Pad Size (Included Gate Pad)	See Die Drawing			
Gate Pad Size	1.11 x 1.10	mm ²		
Area Total / Active	82.26/ 59.1			
Thickness	140	μm		
Wafer Size	200	mm		
Notch Position	0	Degrees		
Maximum-Possible Chips per Wafer	312 pcs.			
Passivation Front side	Silicon Nitride			
Front Metal	Al, Si (4µm)			
Backside Metal	Al (0.1µm), Ti (0.1µm), Ni (0.4µm), Ag (0.6µm)			
Die Bond	Electrically conductive epoxy or solder			
Reject Ink Dot Size	0.25 mm diameter minimum			

Maximum Ratings

	Parameter	Max.	Units
V _{CE}	Collector-Emitter Voltage, TJ=25°C	1200	V
I _C	DC Collector Current	0	A
I _{LM}	Clamped Inductive Load Current ④	300	A
V _{GE}	Gate Emitter Voltage	± 30	V
TJ, T _{STG}	Operating Junction and Storage Temperature	-40 to +175	°C

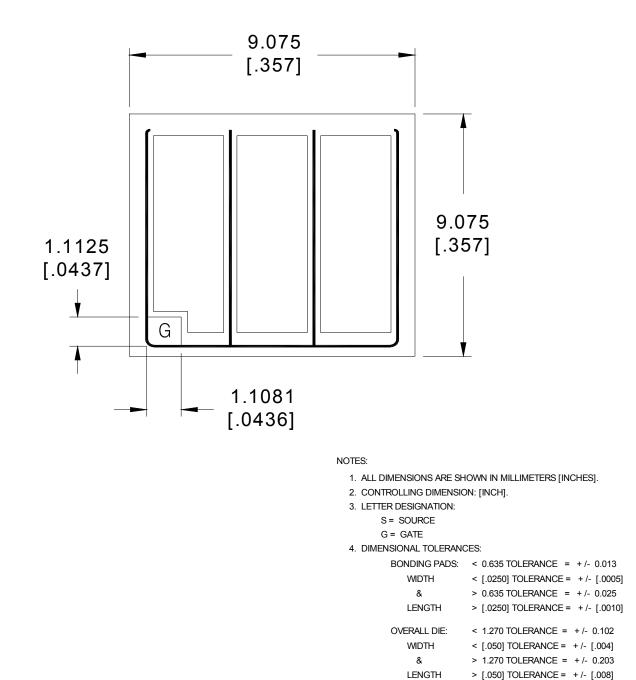
Static Characteristics (Tested on wafers) . T_J=25°C

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)CES}	Collector-to-Emitter Breakdown Voltage	1200			V	V _{GE} = 0V, I _C = 250µA ⑤
V _{CE(sat)}	Collector-to-Emitter Saturated Voltage		1.4	1.6		V _{GE} = 15V, I _C = 20A, T _J = 25°C
V _{GE(th)}	Gate-Emitter Threshold Voltage	5.0		7.5		$I_{C} = 3.5 \text{mA}$, $V_{GE} = V_{CE}$
I _{CES}	Zero Gate Voltage Collector Current		1.0	25	μA	V _{CE} = 1200V, V _{GE} = 0V
I _{GES}	Gate Emitter Leakage Current			± 400	nA	V_{CE} = 0V, V_{GE} = ±30V

	Parameter	Min.	Тур.	Max.	Units	Conditions
\/	Collector to Emitter Saturated Voltage		1.9	2.3	V	$V_{1} = 15V_{1} = 75A_{1} = 25^{\circ}C_{1}$
V _{CE(sat)}	Collector-to-Emitter Saturated Voltage			2.3		$V_{GE} = 15V, I_C = 75A, T_J = 25^{\circ}C$
			2.5			V _{GE} = 15V, I _C = 75A , T _J = 175°C
SCSOA	Short Circuit Safe Operating Area	10			μs	V _{GE} =15V, V _{CC} =600V, ②
						R _G =4.7Ω, V _P ≤1200V,T _J =150°C
		FULL SQUARE			T _J = 175°C, I _C = 300A	
RBSOA	Reverse Bias Safe Operating Area				V _{CC} = 960V, Vp ≤1200V	
						Rg = 4.7 Ω , V _{GE} = +20V to 0V
C _{iss}	Input Capacitance		9450		рF	V _{GE} = 0V
Coss	Output Capacitance		340			V _{CE} = 30V
C _{rss}	Reverse Transfer Capacitance		230			f = 1.0MHz
Qg	Total Gate Charge (turn-on)		360	_	nC	I _C = 75A ⑥
Q _{ge}	Gate-to-Emitter Charge (turn-on)		87			V _{GE} = 15V
Q _{gc}	Gate-to-Collector Charge (turn-on)		180			V _{CC} = 600V

	Parameter	Min.	Тур.	Max.	Units	Conditions ③
t _{d(on)}	Turn-On delay time		63			I _C = 75A, V _{CC} = 600V
t _r	Rise time	—	118	—		R _G = 4.7Ω, V _{GE} =15V, L=200μH
t _{d(off)}	Turn-Off delay time	—	267	—		T _J = 25°C
t _f	Fall time	—	114	_		
t _{d(on)}	Turn-On delay time	—	62	-		I _C = 75A, V _{CC} = 600V
t _r	Rise time	—	110	_		R_{G} = 4.7 Ω , V_{GE} =15V, L= 200 μ H
t _{d(off)}	Turn-Off delay time	—	330	—	1	T _J = 175°C
t _f	Fall time	—	237	_]	

Die Drawing



5. DIE THICKNESS = 0.100 [.0039] - 0.140 [.0055]

Notes:

- ① The current in the application is limited by T_{JMax} and the thermal properties of the assembly.
- ⁽²⁾ Not subject to production test- Verified by design / characterization.
- ③ Values influenced by parasitic L and C in measurement.
- (4) V_{CC} = 80% (V_{CES}), V_{GE} = 20V, L = 200 μ H, R_G = 4.7 Ω .
- S Refer to AN-1086 for guidelines for measuring V_{(BR)CES} safely
- © Die Level Characterization.



Additional Testing and Screening

For Customers requiring product supplied as Known Good Die (KGD) or requiring specific die level testing, please contact your local IR Sales.

Shipping

Sawn Wafer on Film. Please contact your local IR sales office for non-standard shipping options

Handling

- Product must be handled only at ESD safe workstations. Standard ESD precautions and safe work environments are as defined in MIL-HDBK-263.
- Product must be handled only in a class 10,000 or better-designated clean room environment.
- Singulated die are not to be handled with tweezers. A vacuum wand with a non-metallic ESD protected tip should be used.

Wafer/Die Storage

- Proper storage conditions are necessary to prevent product contamination and/or degradation after shipment.
- Note: To reduce the risk of contamination or degradation, it is recommended that product not being used in the assembly process be returned to their original containers and resealed with a vacuum seal process.
- Sawn wafers on a film frame are intended for immediate use and have a limited shelf life.

Further Information

For further information please contact your local IR Sales office or email your enquiry to http://die.irf.com

Data and specifications subject to change without notice. This product has been designed and qualified for Industrial market. Qualification Standards can be found on IR's Web site.

International

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